Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination  LEE, BYOUNG HEON	
09/750,507		
Examiner	Art Unit	
Albert T. Chou	2662	

SEARCHED					
Class	Subclass	Date	Examiner		
455	507	5/3/2005	Ac Ac		
455	509	5/3/2005	AC		
455	456	5/2/2005	AC		
455	457	5/2/2005	AC		
455	458	5/2/2005	AC		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
455	456,1	1/30/06	AC	
455	507	1/30/06	AC	
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